Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10661534	KATAYAMA ET AL.

Examiner
DEVONA E FAULK

Art Unit

2615

SEARCHED						
Class	Subclass	Date	Examiner			
381	105,104,106,102	3/29/07	DEF			
381	311,105,104,311	9/29/07	DEF			
455	41.2,420,430	4/11/08	DEF			

SEARCH NOTES			
Search Notes	Date	Examiner	
Assignee/Inventor Search	3/29/07	DEF	
combined class/word search 381/102-109	3/29,31/07	DEF	
Additional search	9/29/07	DEF	
Reviewed applicant's arguments; maintained rejection	4/11/08	DEF	
Additional search	4/11/08	DEF	
Consulted with Nghi Han Ly of class 455, suggested 455/41.2,420 and 430	4/11/08	DEF	

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	

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